

COMPLIANT HALOGEN FREE

AFN4896S8RG-VB Datasheet N-Channel 100-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^d	Q _g (Typ.)		
100	0.051 at V _{GS} = 10 V	6.8	9 nC		
100	0.069 at V _{GS} = 4.5 V	5.8	9110		

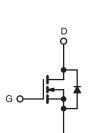
SO-8 S 1 8 D S 2 7 D S 3 6 D G 4 5 D

FEATURES

- Halogen-free According to IEC 61249-2-21 Available
- Trench Power MOSFET
- 100 % UIS Tested

APPLICATIONS

- High Frequency Boost Converter
- LED Backlight for LCD TV



N-Channel MOSFET

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	100	V	
Gate-Source Voltage		V_{GS}	± 20	v
	T _C = 25 °C		6.8	
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C		5.4	
Continuous Drain Current (1) = 150 °C)	T _A = 25 °C	- 'D -	4.4 ^{a, b}	
	T _A = 70 °C		3.5 ^{a, b}	Α
Pulsed Drain Current		I _{DM}	20	
Continuous Source-Drain Diode Current	T _C = 25 °C	lo.	5	
Continuous Source-Drain Diode Current	T _A = 25 °C	Is =	2.1 ^{a, b}	
Single Avalanche Current	L = 0.1 mH	I _{AS}	19	
Single Avalanche Energy	L = 0.1 IIII1	E _{AS}	18	mJ
	T _C = 25 °C		6	
Maximum Dawar Dissination	T _C = 70 °C	P _D	3.8	w
Maximum Power Dissipation	T _A = 25 °C		2.5 ^{a, b}	VV
	T _A = 70 °C		1.6 ^{a, b}	
Operating Junction and Storage Temperature	T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS								
Parameter	Symbol	Typical	Maximum	Unit				
Maximum Junction-to-Ambient ^{b, c}	t ≤ 10 s	R_{thJA}	37	50	°C/W			
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	17	21	7 0/1			

Notes:

- a. Surface Mounted on 1" x 1" FR4 board.
- b. t = 10 s.
- c. Maximum under Steady State conditions is 85 °C/W.
- d. $T_C = 25$ °C.

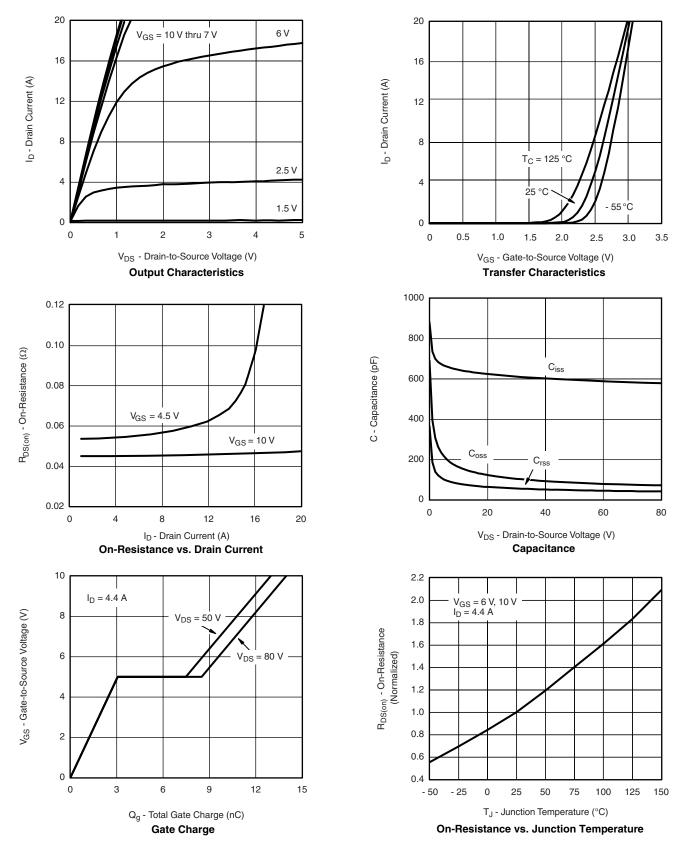


Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static				1			
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	L = 250 HA		120		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 9			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1		2	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zana Oata Vallana Busin Oursell	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V			1		
Zero Gate Voltage Drain Current		$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10	μΑ	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	20			Α	
		V _{GS} = 10 V, I _D = 4.4 A		0.051		†	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 3.8 \text{ A}$		0.069		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 4.4 A		10		S	
Dynamic ^b					L		
Input Capacitance	C _{iss}			600			
Output Capacitance	C _{oss}	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		90		pF	
Reverse Transfer Capacitance	C _{rss}			50			
Total Gate Charge		$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 4.4 \text{ A}$		13.5	5 20		
	Q _g	30 30 3		9	13.5	nC	
Gate-Source Charge	Q_{gs}	$V_{DS} = 50 \text{ V}, V_{GS} = 6 \text{ V}, I_D = 4.4 \text{ A}$		3			
Gate-Drain Charge	Q_{gd}			4.6			
Gate Resistance	R _g	f = 1 MHz		1		Ω	
Turn-On Delay Time	t _{d(on)}			15	25		
Rise Time	t _r	V_{DD} = 50 V, R_L = 14.3 Ω		12	20		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 3.5$ A, V_{GEN} = 6 V, R_g = 1 Ω		12	20		
Fall Time	t _f			10	15		
Turn-On Delay Time	t _{d(on)}			10	15	- ns - -	
Rise Time	t _r	V_{DD} = 50 V, R_L = 14.3 Ω		12	20		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 3.5$ A, V_{GEN} = 10 V, R_g = 1 Ω		15	25		
Fall Time	t _f			10	15		
Drain-Source Body Diode Characteristi	cs						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			5		
Pulse Diode Forward Current	I _{SM}				20	Α	
Body Diode Voltage	V_{SD}	I _S = 3.5 A, V _{GS} = 0 V		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			45	70	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 3.5 A, dI/dt = 100 A/μs, T _J = 25 °C		80	120	nC	
Reverse Recovery Fall Time	t _a	$_{1F} = 3.3 \text{ A}, \text{ u/u} = 100 \text{ A/}\mu\text{s}, 1_{\text{J}} = 25 ^{\circ}\text{C}$		33			
Reverse Recovery Rise Time	t _b			12		ns	

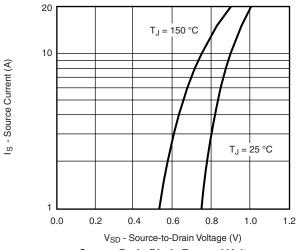
- a. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 % b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

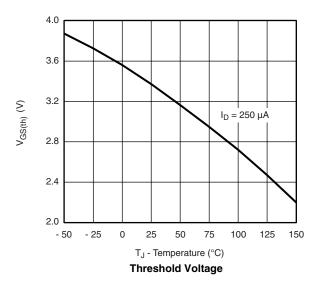


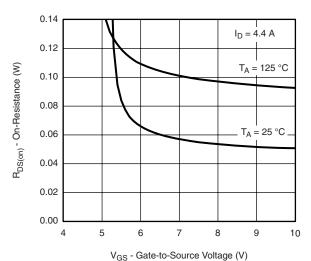




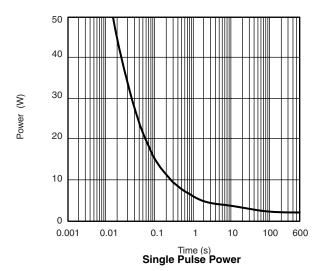


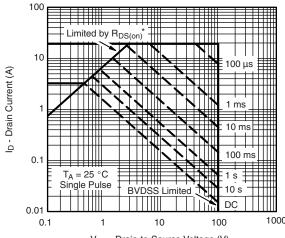
Source-Drain Diode Forward Voltage





On-Resistance vs. Gate-to-Source Voltage

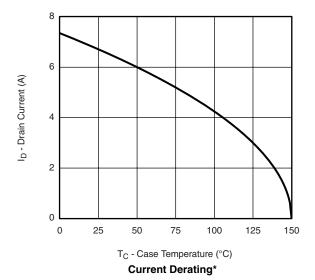


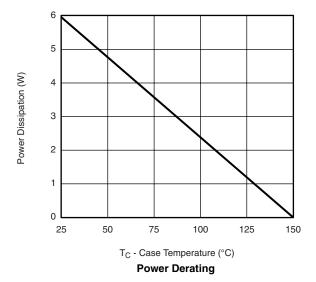


 $\label{eq:VDS} V_{DS} \text{ - Drain-to-Source Voltage (V)} $$^*V_{GS} > \min V_{GS} \text{ at which } R_{DS(on)} \text{ is specified} $$$

Safe Operating Area, Junction-to-Ambient

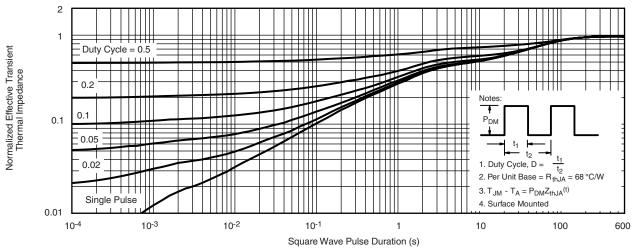




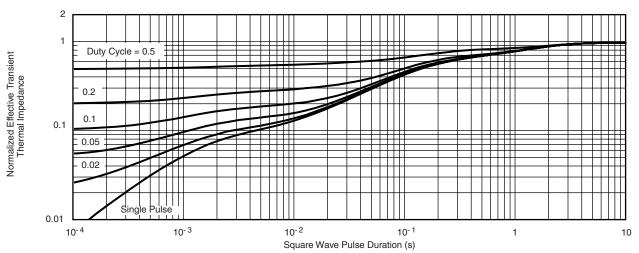


^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





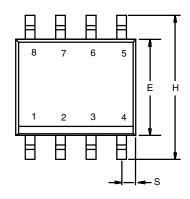
Normalized Thermal Transient Impedance, Junction-to-Ambient

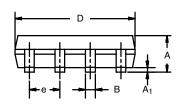


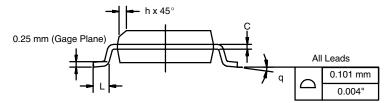
Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012







	MILLIM	IETERS	INCHES		
DIM	Min	Max	Min	Max	
Α	1.35	1.75	0.053	0.069	
A ₁	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
Е	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
ECN: C 06527 Pay 1 11 Cap 06					

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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